



Integrated Device Technology, Inc.  
6024 Silver Creek Valley Road, San Jose, CA - 95138

## PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **TB1604-01**                      DATE: **22-Apr-2016**  
Product Affected:    F1912NCGI, F1912NCGI8  
  
Date Effective:        **22-Jul-2016**

MEANS OF DISTINGUISHING CHANGED DEVICES:  
 Product Mark  
 Back Mark            Traceability to the test location is maintained by IDT and available on request  
 Date Code  
 Other

Contact:            IDT PCN DESK  
  
E-mail:              [pcndesk@idt.com](mailto:pcndesk@idt.com)

Attachment:         Yes             No  
  
Samples:            Please contact your local sales representative for sample request.

**DESCRIPTION AND PURPOSE OF CHANGE:**

- Die Technology
- Wafer Fabrication Process
- Assembly Process
- Equipment
- Material
- Testing
- Manufacturing Site
- Data Sheet
- Other

This notification is to advise our customers that IDT Penang is being added as an alternate facility for Test process for the selective products that are presently tested at Amkor, Korea facility.  
  
Attachment 1 details the change.  
Attachment 2 lists the affected parts.

**RELIABILITY/QUALIFICATION SUMMARY:**

There is no expected change to the product quality or reliability performance. Please refer to Attachment 1 for Electrical correlation data.

**CUSTOMER ACKNOWLEDGMENT OF RECEIPT:**

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.  
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: \_\_\_\_\_  **Approval for shipments prior to effective date.**

Name/Date: \_\_\_\_\_ E-Mail Address: \_\_\_\_\_

Title: \_\_\_\_\_ Phone# /Fax# : \_\_\_\_\_

**CUSTOMER COMMENTS:** \_\_\_\_\_

**IDT ACKNOWLEDGMENT OF RECEIPT:**

RECD. BY: \_\_\_\_\_ DATE: \_\_\_\_\_



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### ATTACHMENT 1 - PCN # : TB1604-01

**PCN Type:** Manufacturing Site - Alternate Test Location

**Data Sheet Change:** None

**Detail Of Change:**

This notification is to advise our customers that IDT Penang is being added as an alternate facility for Test process for the selective products that are presently tested at Amkor, Korea facility.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Tester configuration used at Amkor, Korea is the same as IDT Penang. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

There is no change in the moisture sensitivity level (MSL).

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



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### ATTACHMENT 1 - PCN # : TB1604-01

#### Qualification Information and Qualification Data: Electrical Test Correlation Results

Vehicle: F1912NCGI  
Sample size: 10 electrically good units and 4 golden units

Description	Golden units/ Lab data	Golden units/ ATE data
Tester Platform	Bench equipment	J750
Test Program	N/A	F1912_FT_Rx (where x is program revision)
Test Site	N/A	4
Test Temperature	25°C	25°C
Test Correlation Results	100%	100%
Number of Golden Units Correlated @ ambient	4 pcs	4 pcs
4 units of golden units datalog correlation	Correlated	Correlated
10 units Bin 1 handtest correlation (4 sites)	N/A	Correlated